

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/622,294	CHOWN, DAVID	
Examiner		Art Unit		Page 1 of 1
Li Liu		2613		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,432,874	07-1995	Muraguchi, Takahiro	385/24
*	B	US-6,374,021	04-2002	Nakanishi et al.	385/49
*	C	US-4,904,036	02-1990	Blonder, Greg E.	385/14
*	D	US-5,589,684	12-1996	Ventrudo et al.	250/225
*	E	US-5,710,652	01-1998	Bloom et al.	398/129
*	F	US-5,686,990	11-1997	Laznicka, Jr., Oldrich M.	356/460
*	G	US-5,329,394	07-1994	Calvani et al.	398/152
*	H	US-6,567,195	05-2003	Ford et al.	398/58
*	I	US-6,285,807	09-2001	Walt et al.	385/12
*	J	US-6,869,231	03-2005	Chiu et al.	385/93
*	K	US-6,347,001	02-2002	Arnold et al.	398/122
*	L	US-2001/0048799	12-2001	King et al.	385/125
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.